



## Realizing high-speed testing and high maintainability

The Short-Open Tester FA1221 and In-Circuit Tester FA1220 incorporate a circuit switch (scanner) and resistance meter into a compact enclosure that implements test sequences created using a computer application. An integrated I/O board allows the system to interoperate with external drive systems. By performing tests while moving the workpiece incrementally in the Z-axis direction, the system can automatically verify contact height and contact resistance values.

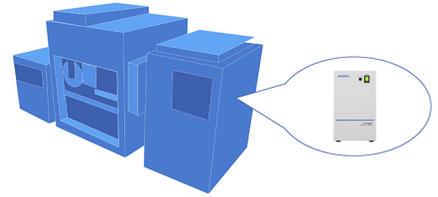
High-speed testing is made possible by the optimized synchronization of the system's built-in scanner and measurement boards.

An optional I/O board can be used to enable interoperability with external drive systems. (Please contact Hioki for more information about support for automation.)

Test data can be created in a short period of time using application software.

Semiconductors are increasingly utilizing new information technologies such as the IoT and AI. Going forward, more and more manufacturing facilities are likely to be faced by the need to achieve both higher quality and shorter test takt times. The Short-Open Tester FA1221 and the In-Circuit Tester FA1220 hold the potential to address the needs of such facilities.

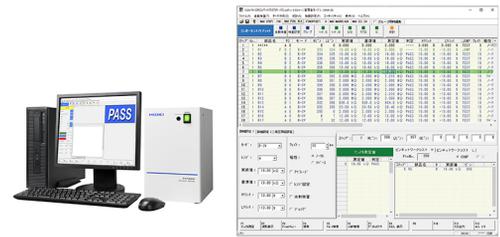
Realizing automation by embedding the system in a drive system



Realizing high-speed, high-precision testing

Model	Maximum number of pins	Test parameters	Measurement range	Measurement speed
FA1221	128 (fixed)	Multi-pin S/O test Resistance measurement (component test)	4Ω to 400kΩ 400μΩ to 40MΩ	From 0.8ms / pin From 0.9ms /step
FA1220	1024 (Expandable in blocks of 128)	Multi-pin S/O test Resistance measurement (component test)	4Ω to 400kΩ 400μΩ to 40MΩ	From 0.8ms / pin From 0.9ms /step

Creating test data quickly



## Flying-probe testers don't need test fixtures

The FA1221 and FA1220, which were introduced in this article, test probe cards and IC test sockets using test fixtures that incorporate probes. However, if the test points on a probe card are too close together, it may not be possible to space the probes on the test fixture closely enough to test the probe card. Additionally, the need to fabricate a test fixture for each probe card increases running costs. In situations such as these, you may wish to consider a flying probe-type tester.



FLYING PROBE TESTER  
FA1240-6x



FLYING PROBE TESTER  
FA1283



FLYING PROBE TESTER  
FA1817